Research Teams

Defect and Material Characterisation

- Pre-irradiation
- Theory
- TSC, DLTS, EPR, PICTS
- SIMS, IR, PL, Hall Effect, FPP

Macroscopic Detector properties

- Detector characteristics (IV, CV, CCE)
- NIEL
- Device modelling
- operational conditions

Defect Engineering

- Oxygenation
- Dimerisation
- other impurities (H, N, Ge,..)
- Thermal Donors technology
- pre-irradiation procedures

New Materials

- SiC
- a-Si
- GaN
- CdTe

New Structures

- 3D
- thin detectors
- Cost-effective solutions

Full Detectors

- LHC-like tests
- links to HEP
- Links to electronics
- pad-mini-full detectors comparison